

# Comparative NH<sub>3</sub> gas sensing characteristics of DC electrochemically deposited Co<sub>3</sub>O<sub>4</sub> films by using different Co-based precursors

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**Abstract:** Herein, a comparative study of NH<sub>3</sub> gas sensing characteristics of DC electrochemically deposited Co<sub>3</sub>O<sub>4</sub> films by using different Co-based precursors is reported. The Co<sub>3</sub>O<sub>4</sub> films are deposited by using DC electrochemical deposition technique on thoroughly cleaned stainless steel (SS) and copper (CU) substrates. The Co<sub>3</sub>O<sub>4</sub> films are deposited by using three water soluble Co-based precursors: (CH<sub>3</sub>COO)<sub>2</sub>Co, Co(NO<sub>3</sub>)<sub>2</sub> and CoCl<sub>2</sub> with CoSO<sub>4</sub>. All as-deposited Co-based films are annealed at 350 °C for 2 hr. All resultant cobalt oxide films are characterized by using X-ray diffraction (XRD) and scanning electron microscopy (SEM). The NH<sub>3</sub> gas sensing characteristics of all resultant films are measured at room temperature by using static gas sensing system at different concentrations between 25 to 350 ppm of NH<sub>3</sub> gas. The structural studies using XRD showed that resultant films contain pure Co<sub>3</sub>O<sub>4</sub> phase with cubic spinel symmetry. The topographical studies using SEM indicated different particle morphology like kite, spherical and interlinked nanowires of Co<sub>3</sub>O<sub>4</sub> films generated by using the CoCl<sub>2</sub> with CoSO<sub>4</sub>, Co(NO<sub>3</sub>)<sub>2</sub> and (CH<sub>3</sub>COO)<sub>2</sub>Co precursors. The NH<sub>3</sub> gas sensing properties of resultant films showed lowest response time for the films generated by using (CH<sub>3</sub>COO)<sub>2</sub>Co precursor. Further, recovery time is found to be lowest for the films generated by using (CH<sub>3</sub>COO)<sub>2</sub>Co precursor on copper substrate. However, sensing studies of resultant films showed that the sensitivity factor (S.F.) is maximum for the films obtained by using the CoCl<sub>2</sub> with CoSO<sub>4</sub> precursor on both SS and CU substrates. For all resultant films, the response time (2 - 5 min.) is found to be higher than the recovery time (25 - 45 sec.). The repeatability and reproducibility in gas sensing characteristic is noted for all films. The highest NH<sub>3</sub> sensing performance of CoCl<sub>2</sub> precursor derived Co<sub>3</sub>O<sub>4</sub> films is linked with morphological characteristics of corresponding films.

**Index Terms** - Co<sub>3</sub>O<sub>4</sub> film; DC Electrochemical deposition; NH<sub>3</sub> sensing; Sensitivity factor.

## 1. INTRODUCTION

The gas sensor is important domain for the field of research in material science. For human health and public safety, the sensor is playing very important at industrial sector and house household level [1- 4]. The NH<sub>3</sub> and LPG sensors are smaller in size, highly sensitive, cheap and easy in manufacturing [5-8]. The NH<sub>3</sub> and LPG sensors have number of applications in environmental, household and industrial problems. The low operating temperature, high stability, fast response, fast recovery, better selectivity, and most importantly high sensitivity are significant characteristics for the development of good sensors [9]. The Co<sub>3</sub>O<sub>4</sub> is an important material for LPG and NH<sub>3</sub> sensing at low operating low temperature [10 - 12]. In view of this, the main objective of present research work was to study the NH<sub>3</sub> sensing response of Co<sub>3</sub>O<sub>4</sub> films. Further, another important objective of present research work was to study the effect of morphology of particles of films on the gas sensing characteristics of Co<sub>3</sub>O<sub>4</sub> films. Hence, for this purpose, cost effective, ease in operation and cheap DC electrochemical deposition technique was used for the preparation of the Co<sub>3</sub>O<sub>4</sub> films. The resultant films were characterized by using X-ray diffraction (XRD) and scanning electron microscopy (SEM) techniques. The NH<sub>3</sub> gas sensing properties were studied by using home-built static gas sensing characterization system. The results obtained related to the materials and NH<sub>3</sub> gas sensing characterization of DC electrochemically deposited Co<sub>3</sub>O<sub>4</sub> films are presented in this communication.

## 2. EXPERIMENTAL DETAILS

### 2.1. Substrate cleaning

The stainless steel and copper substrates were used for the deposition of Co<sub>3</sub>O<sub>4</sub> films. The 0.5 mm thick stainless steel (SS) substrates (area = 2 cm<sup>2</sup>) were cleaned by dipping them for 30 min. in a solution having 50 % HNO<sub>3</sub> and 10 % chromium. Then substrates were cleaned by dipping them for 10 min. in a solution having 10 % H<sub>2</sub>SO<sub>4</sub>. After this substrates were rinsed with acetone to remove effects of prior cleaning. The 0.3 mm thick copper (CU) substrates (area = 2 cm<sup>2</sup>) were cleaned by dipping them for 30 min. in a solution having 670 ml orthophosphoric acid, 100 ml H<sub>2</sub>SO<sub>4</sub> and 270 ml double distilled water (DDW). Then substrates were cleaned by using a solution of salt and lemon in DDW. After this SS and CU substrates were cleaned by using soap solution in DDW. This is followed by rinsing of SS and CU substrates with acetone by dip method. Finally, both substrates were cleaned with dilute detergent and warm water. All the substrates were kept in acetone prior to the deposition of films.

### 2.2. Deposition of cobalt based films

On thoroughly cleaned SS and Cu substrates, the cobalt based films were prepared by using the DC electrochemical deposition technique and different water soluble Co-precursors.

(a) cobalt sulphate [CoSO<sub>4</sub>.7H<sub>2</sub>O] and cobalt chloride [CoCl<sub>2</sub>.4H<sub>2</sub>O] precursors

The CoSO<sub>4</sub>.7H<sub>2</sub>O (0.98 M) and H<sub>3</sub>BO<sub>3</sub> (0.30 M) were dissolved in 500 ml of DDW and solution was filtered using Whatman 41 filter paper. The pH of solution was kept at 4.5 by using NaOH / HCl in solution. It was the deposition bath. The films were deposited at 0.28 M concentration of cobalt chloride (CoCl<sub>2</sub>) in deposition bath. The films were deposited by using the

parameters: cathode-anode distance = 2 cm, current density = 21 mA/cm<sup>2</sup> and deposition time = 15 min. The as-deposited films were washed gently in DDW by dip method. All the as-deposited films were heated at different 350 °C for 2 hr. The films prepared on SS and CU substrates were identified as ESC and EUC respectively.

(b) cobalt nitrate [Co(NO<sub>3</sub>)<sub>2</sub>.6H<sub>2</sub>O] precursor

The Co(NO<sub>3</sub>)<sub>2</sub>.6H<sub>2</sub>O (0.1 M) and H<sub>3</sub>BO<sub>3</sub> (0.12 M) were dissolved in 250 ml of DDW and solution was filtered using Whatman 41 filter paper. The pH of solution was maintained at 4.5 by using NaOH / HCl in solution. It was the deposition bath. The films were deposited at 0.5 M concentration of Co(NO<sub>3</sub>)<sub>2</sub>.6H<sub>2</sub>O in deposition bath. The films were deposited by using the parameters: cathode-anode distance = 2.5 cm, current density = 10 mA/cm<sup>2</sup> and deposition time = 8 min. The deposited films were washed gently in DDW by dip method. The as-deposited films were heated at 350 °C for 2 hr. The films prepared on SS and CU substrates were identified ESN and EUN respectively.

(c) Cobaltous acetate [(CH<sub>3</sub>COO)<sub>2</sub>Co.4H<sub>2</sub>O] precursor

The (CH<sub>3</sub>COO)<sub>2</sub>Co.4H<sub>2</sub>O (0.1 M) and H<sub>3</sub>BO<sub>3</sub> (0.15 M) were dissolved in 250 ml of DDW and solution is filtered using Whatman 41 filter paper. The pH of solution was kep at 4.5 by using NaOH/ HCl. It was deposition bath. The films were deposited at 0.7 M concentration of (CH<sub>3</sub>COO)<sub>2</sub>Co.4H<sub>2</sub>O in deposition bath. The films were deposited by using the parameters: cathode-anode distance = 2.5 cm, current density = 10 mA/cm<sup>2</sup> and deposition time = 12 min. The films were washed gently in DDW by dip method. The as-deposited films were heated at 350 °C for 2 hr. The films prepared on SS and CU substrates were identified as ESA and EUA respectively.

### 2.3. Characterization of as-prepared films

The as-prepared films were characterized by different physical techniques. The X-ray diffractometer (Bruker AXS, D8 Advanced) was used for structural analysis of films. The scanning electron microscope (SEM, JEOL JSM-6360-LA) was used for study of morphological features like particle size, shape and particle size distribution in resultant films. The NH<sub>3</sub> gas sensing characteristics: sensitivity factor (S.F.), response time, recovery time, repeatability and reproducibility of different as-prepared films were recorded by using home-built static gas sensing system at room temperature (RT).

## 3. RESULTS AND DISCUSSION

### 3.1. X-ray diffraction studies

The formation of cobalt oxide in resultant films deposited on SS and CU substrates was studied by using X-ray diffraction patterns. Fig. 1 gives the X-ray diffraction patterns for the films deposited on SS and CU substrates by using the different cobalt precursors. In all XRD patterns, reflections corresponding to the face centered cubic, CoO [JCPDS, PDF-71-1178] and hexagonal CoO(OH) [JCPDS, PDF-74-1057] are not observed [1- 4]. All peaks observed in XRD patterns are found to be perfectly matching with the reflections given for cubic spinel Co<sub>3</sub>O<sub>4</sub> in JCPDS data file: PDF-76-1802. The values of lattice parameter are found to be very close to the reported value (8.084 Å) for cubic spinel Co<sub>3</sub>O<sub>4</sub> phase [12]. This indicates that films deposited by using electrochemical deposition technique on SS and CU substrates contain pure single phase Co<sub>3</sub>O<sub>4</sub> with cubic spinel symmetry when annealed at 350° C for 2 hr.

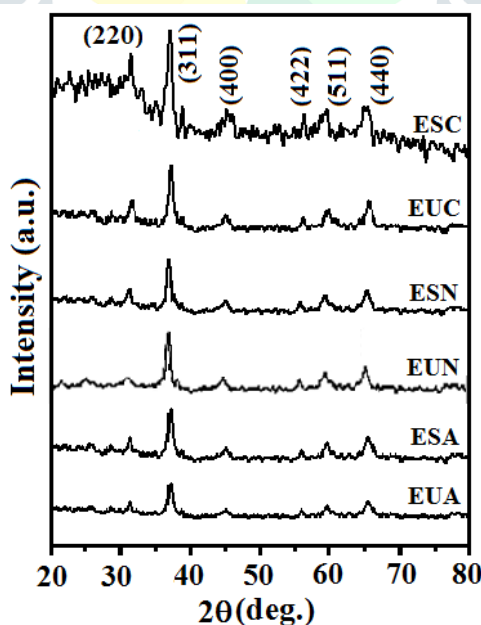


Fig. 1 X-ray diffraction patterns for the films deposited on SS and CU substrates by using the different cobalt precursors

### 3.2. Scanning electron microscopy

For morphological study of the resultant films, the scanning electron microscopy (SEM) study was undertaken. Fig. 2 shows the scanning electron microphotographs of the resultant films. The following observations are noted for ESC and EUC films. The shape of each particle is diamond-like and each particle contains the different thin layers of diamond like structures. The diamond-like particles are hard agglomerates or dense. The particle size distribution is nearly uniform. The numbers of voids are observed on the surface of films indicating thereby less densification and high surface roughness of each film. The average particle size is found to be ~ 1 μm. In case of films ESN and EUN, the spherical morphology is observed. The hard and soft agglomerates are observed in ESN and EUN films deposited on SS and CU substrates respectively. The size of the spherical agglomerates is in range of 1-3 μm.

The particle size distribution is almost uniform in these films. The voids also observed on the surface of these films showing thereby lower densification and high surface roughness in these films. Entirely different observations are found in case of ESA and EUA films. The surface of each film is found to be covered with the mesh of wires. The surface is flat at the bottom of the mesh of interlinked wires. These interlinked wires are found to be attached firmly to flat surface with the insertion of ends of wires into the surface at different points. The wires are dense and diameters of wire are found to be in range of 250 - 350 nm. Further, the lengths of the wire are found to be in the range of 2 - 10  $\mu\text{m}$ . The mesh of interlinked wire structure is not very dense. However, the flat surface below the wired mesh structure is dense. Qualitatively, the adhesion of all the films to surface is noted to be very good.

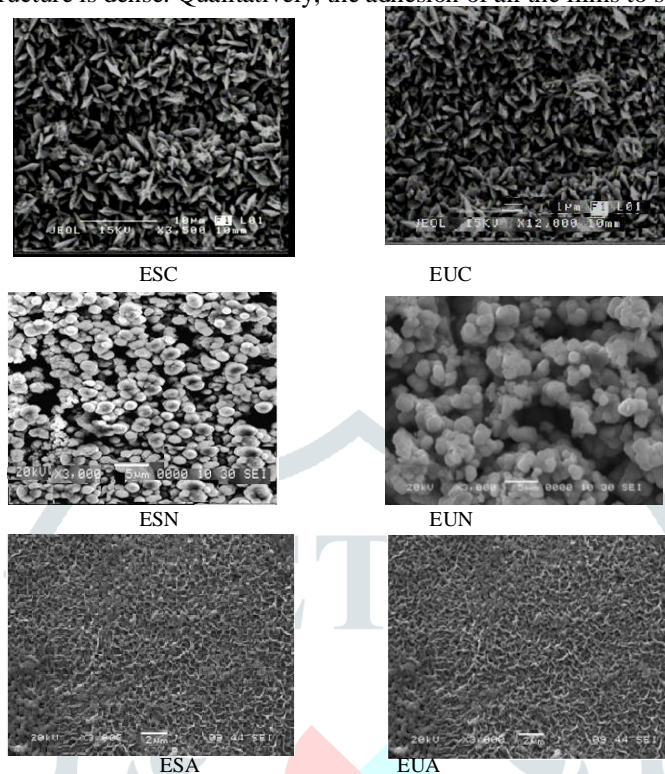


Fig. 2 SEM photographs for the films deposited on SS and CU substrates by using the different cobalt precursors

### 3.3. $\text{NH}_3$ sensing properties

Fig. 3 shows the variation of sensitivity factor (SF) with  $\text{NH}_3$  gas concentration (in ppm) for the films deposited on SS and CU substrates by using the different cobalt precursors. For all films, initially, the SF is found to be increasing with increasing the  $\text{NH}_3$  gas concentration to a certain value. After this, SF saturates to a constant value. The SF saturates above  $\sim 150$  ppm concentration of  $\text{NH}_3$  gas for the ESC, EUC, ESN and EUN films. However, for the ESA and EUA films the SF saturates above  $\sim 100$  ppm concentration of  $\text{NH}_3$  gas. The maximum values of SF are found to be 255 and 270 for the ESC7 and EUC7 films respectively. Further, the maximum values of SF are found to be 115 and 136 for the ESN5 and EUN5 films respectively. Furthermore, the maximum values of SF are found to be 155 and 145 for the ESA5 and EUA5 films respectively. The  $\text{NH}_3$  gas sensing data properties: highest values of SF, response time and recovery time are summarized in Table 1.

The highest values of sensitivity factor are found to be decreasing in the order (ESC, EUC), (ESA, EUA) and (ESN, EUN) as far as the cobalt precursor is concerned. Further, the SF is found to be higher for the films deposited on the CU substrate as compared to the films deposited on SS substrate. For all the films the response time is found to be much higher than the recovery time. The response time is of the order of few minute whereas the recovery time is of the order of second. This indicates the slow response of all the films in the presence of  $\text{NH}_3$  gas. However, recovery of all sensor films is very fast on exposure of them to the air atmosphere. Further, response of ESA and EUA films to  $\text{NH}_3$  gas sensing is faster as compared to the other films: ESC, EUC, ESN and EUN. Furthermore, the recovery of ESA and EUA films is also faster as compared to the other films: ESC, EUC, ESN and EUN. For all films, both response and recovery time are found to lower for the films deposited on CU substrates as compared to the films generated on the SS substrates.



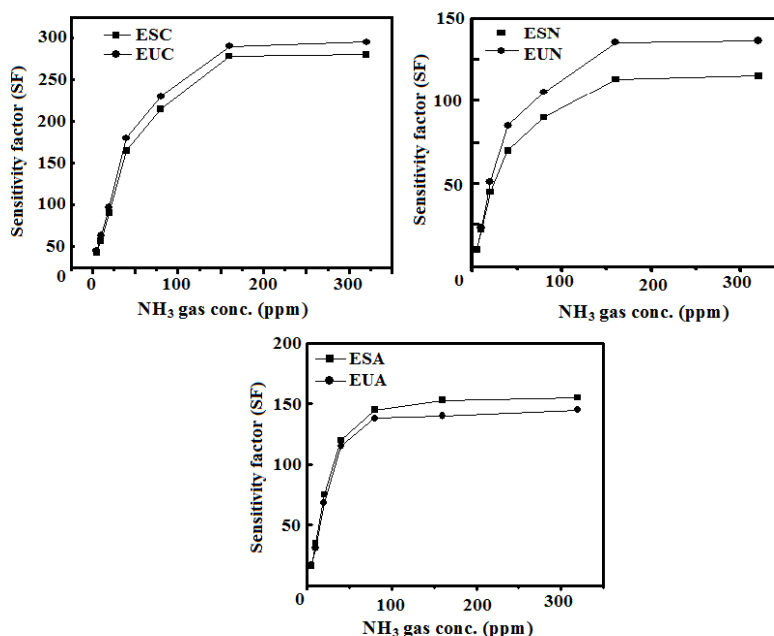


Fig. 3 Variation of sensitivity factor (SF) with  $\text{NH}_3$  gas concentration (in ppm) for the films deposited on SS and CU substrates by using the different cobalt precursors

Table 1  $\text{NH}_3$  gas sensing data properties for the films deposited on SS and CU substrates by using the different cobalt precursors

Film name	Response time (min.)	Recovery time (sec.)	Sensitivity Factor (SF)
ESC	4.25	40	255
EUC	3.75	33	270
ESN	4.50	45	115
EUN	3.75	35	136
ESA	2.25	30	155
EUA	2.50	25	145

The repeatability of  $\text{NH}_3$  gas sensing characteristics of all films was noted by measuring the gas sensing behavior of these films for number of the cycles. The  $\text{NH}_3$  gas sensing behavior along-with the highest value of SF was found to be nearly constant in all the cycles for each film. This confirms the repeatability of  $\text{NH}_3$  gas sensing characteristics of all films. Further, the gas sensing characteristics were also recorded for these films generated from the different batches of preparation. The almost similar gas sensing properties were found for these films generated from the different batches of preparation. This confirms the reproducibility of gas sensing properties of resultant films.

The gas sensing properties of the films deposited on SS and CU substrates by using the different cobalt precursors  $\text{CoCl}_2$  with  $\text{CoSO}_4$ ,  $\text{Co}(\text{NO}_3)_2$  and  $(\text{CH}_3\text{COO})_2\text{Co}$  can be linked with the morphological features of the surface of these films. The highest  $\text{NH}_3$  gas sensing performance obtained for ESC and EUC films can be linked with the special microstructure resulted in these films. In this case, the highest gas sensing properties might be due to diamond like structure of agglomerated  $\text{Co}_3\text{O}_4$  particles. Further, each particle contains the different thin layers of diamond like structures with voids at surface of each films. These features give the high surface area leading to enhanced gas sensing characteristics. In case of ESA and EUA films, again special microstructure namely mesh of interlinked nanowires is obtained. However, the base of this mesh of interlinked nanowires is dense. This decreases the surface area leading to lower value of  $\text{NH}_3$  gas sensing characteristics for ESA and EUA films as compared to ESC and EUC films. In case of ESN and EUN films, more voids are seen as compared to the ESC, EUC an ESA, EUA films. However, particles are hard and soft agglomerates. The particle size is higher in case of ESN and EUN films as compared to the ESC, EUC an ESA, EUA films. This has reduced further surface area of particles of ESN and EUN films. Due to this the  $\text{NH}_3$  gas sensing properties particles of ESN and EUN films also further reduced. The lower response time in case of ESA and EUA films might be due to the interlinked nanowired structure present at the surface these films.

#### 4. CONCLUSIONS

The DC electrochemical deposition is cheap-simple method for the preparation of films and needs less instrumentation. The  $\text{Co}_3\text{O}_4$  films deposited by using this technique are uniformly thick with better adhesion to substrates. The  $\text{NH}_3$  gas sensing properties of  $\text{Co}_3\text{O}_4$  films deposited by using the different Co-precursors are found to be depending on the morphology of particles of films. Further, morphology of particles is found to be depending on the precursor used for the deposition of the films. For all films, response time is found to be much higher than the recovery time. The  $\text{Co}_3\text{O}_4$  films deposited by using the  $\text{CoSO}_4$  and  $\text{CoCl}_2$  precursors are found to better for  $\text{NH}_3$  sensing.

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